

# SIS412DN-T1-GE3-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	$R_{DS(on)}\left(\Omega\right)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
30	0.021 at V <sub>GS</sub> = 10 V	18	3.8 nC			
30	0.025 at V <sub>GS</sub> = 4.5 V	17	3.6110			

#### **FEATURES**

- Halogen-free According to IEC 61249-2-21
- Trench Power MOSFET
- 100 % R<sub>a</sub> Tested



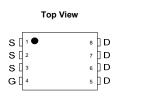
ROHS

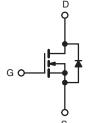
#### DFN 3x3 EP



#### **APPLICATIONS**

- Notebook PC
  - System Power
  - Load Switch





N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	$V_{DS}$	30	V	
Gate-Source Voltage	$V_{GS}$	± 20	v	
	T <sub>C</sub> = 25 °C		18 <sup>a</sup>	
Continuous Drain Current (T <sub>.I</sub> = 150 °C)	$T_C = 70  ^{\circ}C$	I <sub>D</sub>	11 <sup>a</sup>	
communication can can (i.g. let c)	T <sub>A</sub> = 25 °C	υ.	9 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C		7 <sup>b, c</sup>	Α .
Pulsed Drain Current	I <sub>DM</sub>	35		
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	l-	12 <sup>a</sup>	
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	ls –	2.7 <sup>b, c</sup>	
Single Pulse Avalanche Current L = 0.1 mH		I <sub>AS</sub>	5	
Single Pulse Avalanche Energy	_ L = 0.111111	E <sub>AS</sub>	1.25	mJ
	T <sub>C</sub> = 25 °C		15.6	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C	$P_{D}$	10	W
Maximum Fower Dissipation	T <sub>A</sub> = 25 °C	1 'D	3.2 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C		2 <sup>b, c</sup>	
Operating Junction and Storage Temperature	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	
Soldering Recommendations (Peak Tempera		260		

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b, d</sup>	t ≤ 10 s	$R_{thJA}$	32	39	°C/W		
Maximum Junction-to-Case (Drain)	Steady State	$R_{thJC}$	6.5	8			

#### Notes

- a. Package Limited.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under Steady State conditions is 81 °C/W.
- e. The DFN 3x 3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- f. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.



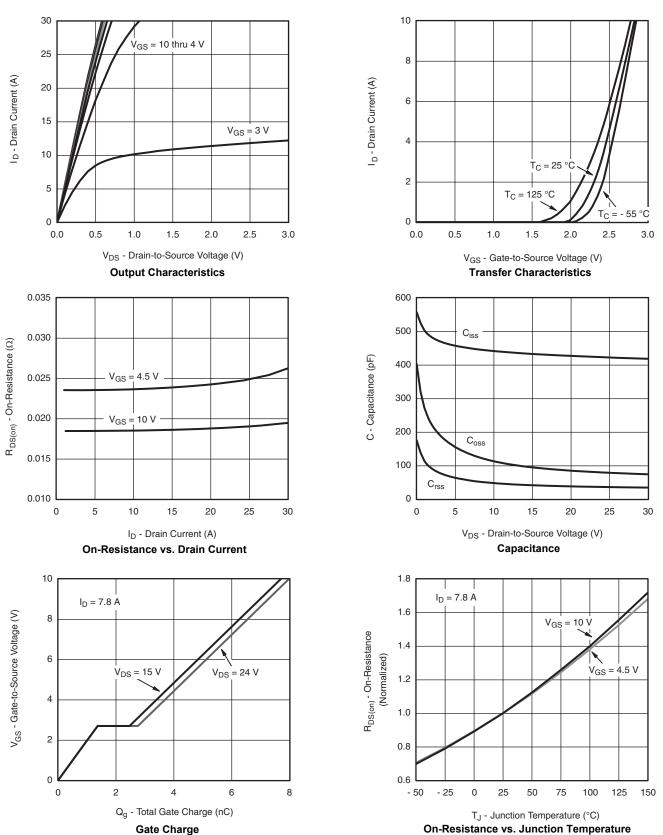
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	1			1	I.	•
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = 250 μA		35		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA		- 4.5		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1.0		2.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Oata Wallana Busin Oamant	I <sub>DSS</sub>	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current		V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			5	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	20			Α
_		$V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A}$		0.021		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 7.0 \text{ A}$		0.025		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 7.8 A		17		S
Dynamic <sup>b</sup>	<u> </u>	- <del>-</del>				1
Input Capacitance	C <sub>iss</sub>			435		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		95		
Reverse Transfer Capacitance	C <sub>rss</sub>			42		
Total Cata Chausa		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 7.8 \text{ A}$	8	12		
Total Gate Charge				3.8	6	nC
Gate-Source Charge	$Q_{gs}$	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 7.8 \text{ A}$		1.4		
Gate-Drain Charge	$Q_{gd}$			1.1		
Gate Resistance	$R_{g}$	f = 1 MHz	1.5	3.2	4.5	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			15	25	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 2.4 $\Omega$		12	20	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 6.3$ A, $V_{GEN}=4.5$ V, $R_g=1~\Omega$		13	20	
Fall Time	t <sub>f</sub>			10	15	
Turn-On Delay Time	t <sub>d(on)</sub>			5	10	ns -
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 2.4 $\Omega$		10	15	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 6.3$ A, $V_{GEN}$ = 10 V, $R_g$ = 1 $\Omega$		15	25	
Fall Time	t <sub>f</sub>			10	15	1
<b>Drain-Source Body Diode Characteristi</b>	cs					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C		12		Δ
Pulse Diode Forward Current	I <sub>SM</sub>				35	Α
Body Diode Voltage	$V_{SD}$	$I_S = 6.3 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			15	25	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>F</sub> = 6.3 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C		7	12	nC
Reverse Recovery Fall Time	t <sub>a</sub>	1 <sub>F</sub> = 0.5 Λ, αι/αι = 100 Α/μs, 1 <sub>J</sub> = 25 °C		9		20
Reverse Recovery Rise Time	t <sub>b</sub>			6		ns

#### Notes:

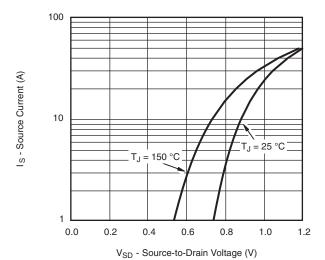
- a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

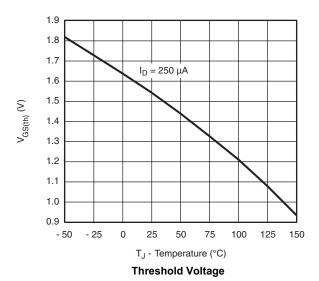


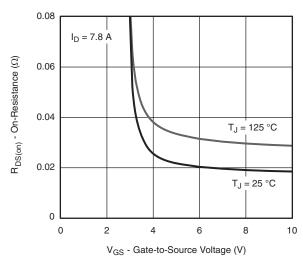




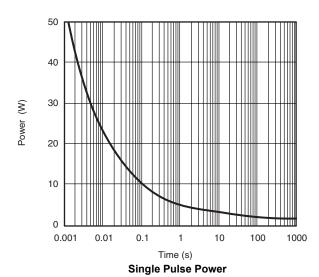


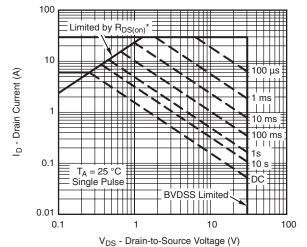
#### Source-Drain Diode Forward Voltage





On-Resistance vs. Gate-to-Source Voltage

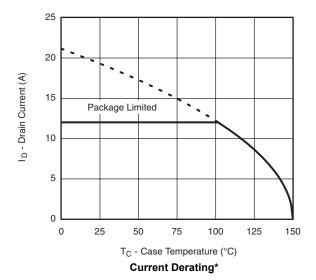


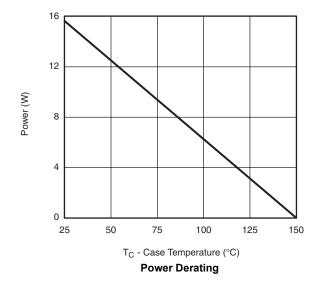


\* V<sub>GS</sub> > minimum V<sub>GS</sub> at which R<sub>DS(on)</sub> is specified

Safe Operating Area, Junction-to-Ambient

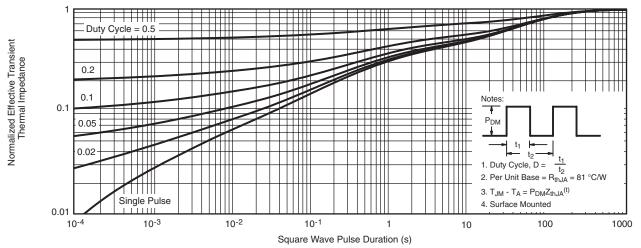






<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





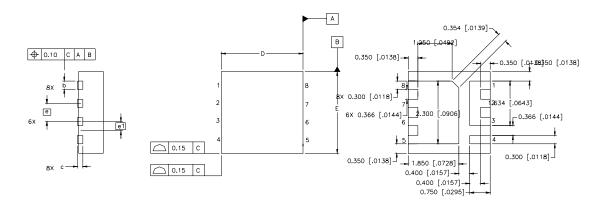
#### Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

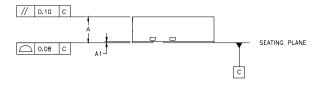


### **PQFN Package Details**



SIDE VIEW TOP VIEW

BOTTOM VIEW

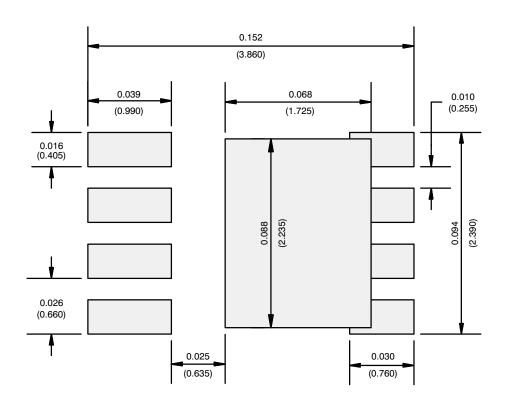


FRONT VIEW

DIM	INCH	IES	MILLIMETERS		
	MIN	MAX	MIN	MAX	
А	.0315	.0394	0.800	1.000	
A1	.0000	.0020	0.000	0.050	
b	.0098	.0138	0.250	0.350	
С	.0080 REF.		0.203 REF.		
D	.1181	BASIC	3.000	BASIC	
E	.1181	BASIC	3.000	BASIC	
е	.0262	BASIC	0.666	BASIC	
e1	.0131	BASIC	0.333	BASIC	



#### **RECOMMENDED MINIMUM PADS**



Recommended Minimum Pads Dimensions in Inches/(mm)



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